

## [Introduction]

Environmental conditions have a great influence on the functionality and reliability of the electronic components, devices and systems. A normal temperature test is often not sufficient to detect latent weak points as quickly as possible. Samples must be subjected to multiple, shock like temperature changes. With thermal shock test chamber extremely fast temperature changes from – 55 °C to +150 °C can be achieved. This helps you to reduce early failures and to increase the reliability of your products. Reproducible, certified and under accelerated conditions.

## [Performances]

Two-zone Shock Test Chambers		TS2-36	TS2-80	TS2-150
Test space volumes	L	36	80	150
Test space dimensions, H x W x D, approx.	mm	400*300*300	500*400*400	600*500*500
Exterior housing dimensions machine unit, H x W x D, approx.	mm	1110*1870*1360	1210*1970*1 <mark>4</mark> 60	1310*2070*2420
Temperature range hot chamber	°C	+40 to +200	+40 to +200	+40 to +220
Temperature range cold chamber	°C	- 75 to 0	- 75 to 0	- 75 to 0
Exposure temperature	°C	-55 to 150	-55 to 150	-55 to 150
Heating rate hot chamber	°C/min	17.0	14.0	11.0
Cooling rate cold chamber	°C/min	3.7	6.3	5.0
Heating rate cold chamber single chamber operation	°C/min	3.2	2.0	1.5
Temperature deviation in time	°C	$\pm 2$	± 2	± 2
Temperature homogeneity in space	°C	≤2	≤2	≤2
l'emperature stability	°C	±0.5	±0.5	±0.5
Maximum load movable basket	kg	30	30	30
Changeover time between hot/cold chamber	sec	<10	<10	<10
Temperature recovery time	min	≤5min	≤5min	≤5mir

[Features]

Quality assurance: The chamber is designed according to the international standard, core components are all from the global renowned brand.Easy control: 7 inches color touch control panel with large data storage of 1200

days, automatically analyse failure and display measures.

\*Short preheat or precool waiting time and defrosting.

